

Notice of References Cited	Application/Control No. 10/711,709		Applicant(s)/Patent Under Reexamination VERSIC ET AL.	
	Examiner Kimberly D. Nguyen		Art Unit 2876	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,951,596	10-2005	Green et al.	156/264
*	C	US-5,059,471	10-1991	McNally et al.	428/143
*	D	US-6,940,408	09-2005	Ferguson et al.	340/572.7
*	E	US-6,518,887	02-2003	Suzuki et al.	340/572.8
*	F	US-6,951,596	10-2005	Green et al.	156/264
*	G	US-7,102,520	09-2006	Liu et al.	340/572.1
*	H	US-6,607,135	08-2003	Hirai et al.	235/487
*	I	US-7,061,083	06-2006	Usami et al.	257/679
*	J	US-2004/0159709	08-2004	Ohta et al.	235/492
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yoshihara et al (DE 19957111 A1), Semiconductor component, e.g. wafer of sensor..., 31 May 2000.
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.